Application/Control No.	Applicant(s)/Patent und Reexamination	ler	
10/808,370	YAMANAKA, TAKASHI		
Examiner	Art Unit		
Rvan D. Walsh	2852		

SEARCHED						
Class	Subclass	Date	Examiner			
399	122	2/10/2006	RDW			
399	107	2/10/2006	RDW			
399	320	2/10/2006	RDW			
399	1	2/13/2006	RDW			
399	411	2/13/2006	RDW			
updata	debove	8/15/04	ROW			
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
L14 attached East		2/13/2006	RDW	
L5+L6		8/15/06	RUL	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
US and Foreign class and text search East attached Updateel	2/10/2006 8/15/66	RDW RDL		
. Arthur Grimley	2/10/2006	RDW		